

Erratum to: A Small Chip Area Stochastic Calibration for TDC Using Ring Oscillator

Kentaroh Katoh · Yutaro Kobayashi · Takeshi Chujo ·
Junshan Wang · Ensi Li · Congbing Li ·
Haruo Kobayashi

Published online: 23 December 2014
© Springer Science+Business Media New York 2014

Erratum to: J Electron Test (2014) 30(6):653–663
DOI 10.1007/s10836-014-5486-0

The original version of this article unfortunately contained the following mistakes.

1. Below the title and in biography, an author's name Congbing Li is spelled incorrectly.
2. In the biography of Kentaroh Katoh, Since 2011, he has been a member of Tsuruoka National College of Technology. → Since 2011, he has been a member of National Institute of Technology, Tsuruoka College. He is currently a research staff of Gunma University, too. → He was a visiting researcher of Gunma University in 2013.

The online version of the original article can be found at <http://dx.doi.org/10.1007/s10836-014-5486-0>.

K. Katoh (✉)
National Institute of Technology, Tsuruoka College, Tsuruoka,
Yamagata, 997-8511, Japan
e-mail: k-katoh@tsuruoka-nct.ac.jp

Y. Kobayashi · T. Chujo · J. Wang · E. Li · C. Li · H. Kobayashi
Division of Electronics and Informatics, Faculty of Science and
Technology, Gunma University, 1-5-1 Tenjin-cho, Kiryu,
Gunma, 376-8515, Japan

Y. Kobayashi
e-mail: t10306028@gunma-u.ac.jp

T. Chujo
e-mail: t10306054@gunma-u.ac.jp

J. Wang
e-mail: t10306902@gunma-u.ac.jp

E. Li
e-mail: t13801499@gunma-u.ac.jp

C. Li
e-mail: t13802483@gunma-u.ac.jp

H. Kobayashi
e-mail: k_haruo@el.gunma-u.ac.jp